

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/728,972	HSIEH, CHIH-WEI	
		Examiner	Art Unit	Page 1 of 1
		Gail Verbitsky	2859	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0105487	06-2004	Chen, Sanlian	374/163
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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